

Table 1. Instrument parameters used for X-ray powder diffraction Rietveld refinement.

Geometry: Bragg-Brentano	Divergence slit: fixed = 1.0°
Radiation source: Cu K α	Receiving slit: 0.3 mm
Generator: 40 kV, 40 mA	Detector: scintillation counter
Tube: 12 mm long line focus	Step size: 0.02°
Scan mode: $\theta/2\theta$	Time per step: 10 s
Secondary monochromator: graphite	Angular range: 10–140 ° 2θ
Primary and secondary Soller slits: 6.0°	Mean temperature of measurement: ~22°C

Table 2.

Summary of the parameters refined and derived for crystal-chemical (C-CH) and standard crystallographic (CRYST) refinement models. Please refer to Table 1 in Mercier *et al.* (2005) for all parameter definitions and symbols, as well as all equations necessary to obtain the parameters derived from those that are refined.

	C-CH	CRYST
Parameters refined:	$d_{\text{Al-O1}}$, $\Delta_{\text{Al-O}}$, δ_{Al} , α_{Al} , $d_{\text{B-O}}$, $\tau_{\text{O-B-O}}$, ρ_{AlII} , α_{AlII} , $d_{\text{AlII-O3}}$, $\phi_{\text{O3-AlII-O3}}$	a , c , Alz , $\text{AlI}x$, $\text{AlI}y$, Bx , By , $\text{O1}x$, $\text{O1}y$, $\text{O2}x$, $\text{O2}y$, $\text{O3}x$, $\text{O3}y$, $\text{O3}z$
	(total =10)	(total =14)
Parameters derived:	a , c , $\psi_{\text{Al-O1}}$, η , Alz , $\text{AlI}x$, $\text{AlI}y$, Bx , By , $\text{O1}x$, $\text{O1}y$, $\text{O2}x$, $\text{O2}y$, $\text{O3}x$, $\text{O3}y$, $\text{O3}z$	(Al-O1) , $(\text{Al-O1})^{\text{Alz}=0}$, $\Delta_{\text{Al-O}}^{\text{Alz}=0}$, δ_{Al} , α_{Al} , $\langle \text{B-O} \rangle$, $\langle \tau_{\text{O-B-O}} \rangle$, ρ_{AlII} , (AlII-X) , α_{AlII} , (AlII-O3) , $\phi_{\text{O3-AlII-O3}}$, $\psi_{\text{Al-O1}}^{\text{Alz}=0}$

Table 6. Continued.

